

Study of ion implanted Fe depth distribution in Si after pulsed ion beam treatment

Angelov, Christo; Georgiev, S.; Amov, Blagoj; Goranova, E.; **Mikli, Valdek**; Dezsi, I.; Kotai, E. Journal of optoelectronics and advanced materials 2007 / 2, p. 307-310

https://www.researchgate.net/publication/289186791_Study_of_the_ion_implemented_Fe_depth_distribution_in_Si_after_pulsed_ion_beam_treatment